

Search Notes

Application/Control No.

10/500,581

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

TAKENAKA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	52	7/25/2005	HN
310	54	7/25/2005	HN
310	58	7/25/2005	HN
310	64	7/25/2005	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR